



Quad 8-Bit CMOS D/A Converter with Internal 10 V Reference

DAC-8426

1.1 Scope.

This specification covers the detail requirement for a quad 8-bit CMOS digital-to-analog converter with output voltage amplifiers and internal 10 V voltage reference. The internal latches provide direct interface for most microprocessors. The DAC-8426 operates with either a dual or single power supply.

It is highly recommended that this data sheet be used as a baseline for new military or aerospace specification control drawings.

1.2 Part Number.

The complete part numbers per Table 1 of this specification is as follows:

| Device | Part Number | Package |
|--------|----------------|---------|
| -1 | DAC-8426AR/883 | R |

1.2.3 Case Outline.

| Letter | Case Outline (Lead Finish per MIL-M-38510) |
|--------|---|
| R | 20-Lead Ceramic Dual-in-Line Package (Cerdip) |

1.3 Absolute Maximum Ratings. ($T_A = +25^\circ\text{C}$ unless otherwise noted)

| | |
|--------------------------------------|---------------------|
| V_{DD} to AGND or DGND | -0.3 V, +17 V |
| V_{SS} to AGND or DGND | -7 V, V_{DD} |
| V_{DD} to V_{SS} | -0.3 V, +24 V |
| AGND to DGND | -0.3 V, +5 V |
| Digital Input Voltage to DGND | -0.3 V, V_{DD} |
| V_{REFOUT} to AGND | -0.3 V, V_{DD} |
| V_{OUT} to AGND | V_{SS} , V_{DD} |
| Power Dissipation to +75°C | 500 mW |
| Derate above 75°C by | 6.4 mW/°C |
| Operating Temperature Range | -55°C to +125°C |
| Junction Temperature Range (T_J) | -65°C to +150°C |
| Storage Temperature Range | -65°C to +150°C |
| Lead Temperature (Soldering 60 sec) | +300°C |

1.5 Thermal Characteristics.

| | |
|----------------------------------|--------------------------|
| Thermal Resistance θ_{JC} | 7°C/W |
| θ_{JA} | 70°C/W max |

DAC-8426—SPECIFICATIONS

Table 1.

| Test | Symbol | Device Types | Limits | | Group A Subgroups | Conditions ¹ | Units |
|--|---------------------|--------------|--------|-------|-------------------|--|-------|
| | | | Min | Max | | | |
| Resolution | N | All | 8 | | 1, 2, 3 | T _A = +25°C, -55°C & +125°C | Bits |
| Total Unadjusted Error | TUE | All | -1 | ±1 | 1, 2, 3 | Includes Reference ² T _A = +25°C, -55°C & +125°C | LSB |
| | | | -2 | ±2 | 1, 2, 3 | | |
| Relative Accuracy | INL | All | -1 | ±1/2 | 1, 2, 3 | T _A = +25°C, -55°C & +125°C | LSB |
| | | | -2 | ±1 | 1, 2, 3 | | |
| Differential Nonlinearity | DNL | All | | ±1 | 1, 2, 3 | Note 3; T _A = +25°C, -55°C & +125°C | LSB |
| Zero Scale Error | V _{ZSE} | All | | 20 | 1, 2, 3 | V _{SS} = -5 V; T _A = +25°C, -55°C & +125°C | mV |
| Reference Output Voltage | V _{REFOUT} | All | 9.96 | 10.04 | 1, 2, 3 | No Load; T _A = +25°C, -55°C & +125°C | V |
| | | | -2 | 9.92 | | | |
| Reference Load Regulation | LD _{REG} | All | | 0.1 | 1, 2, 3 | ΔI _L = 10 mA; T _A = +25°C, -55°C & +125°C | %/mA |
| Reference Line Regulation | LN _{REG} | All | | 0.04 | 1, 2, 3 | ΔV _{DD} = ±10%; T _A = +25°C, -55°C & +125°C | %/mA |
| Reference Output Current | I _{REFOUT} | All | 5 | | 1, 2, 3 | ΔV _{REFOUT} < 40 mV; T _A = +25°C, -55°C & +125°C | mA |
| Logic Input "0" | V _{INL} | All | | 0.8 | 1, 2, 3 | T _A = +25°C, -55°C & +125°C | V |
| Logic Input "1" | V _{INH} | All | 2.4 | | 1, 2, 3 | T _A = +25°C, -55°C & +125°C | V |
| Logic Input Current | I _{IN} | All | | 10 | 1, 2, 3 | V _{IN} = 0 V or V _{DD} ; T _A = +25°C, -55°C & +125°C | μA |
| Positive Supply Current ³ | I _{DD} | All | | 14 | 1, 2, 3 | T _A = +25°C, -55°C & +125°C | mA |
| Negative Supply Current ³ | I _{SS} | All | | 10 | 1, 2, 3 | Dual Supply, V _{SS} = -5 V; T _A = +25°C, -55°C & +125°C | mA |
| Power Supply Sensitivity | PSS | All | | 0.01 | 1, 2, 3 | ΔV _{DD} = ±10%; T _A = +25°C, -55°C & +125°C | %/% |
| Output Source Current | I _{OUT} | All | 10 | | 1, 2, 3 | Digital Inputs All Ones; T _A = +25°C, -55°C & +125°C | mA |
| Output Sink Current | I _{OUT-} | All | 0.35 | | 1, 2, 3 | Digital Inputs All Zeros | mA |
| V _{OUT} Settling Time (Positive or Negative) | t _S | All | | 5 | 9 | T _O ±1/2 LSB; T _A = +25°C | μs |
| Address to Write Setup Time | t _{AS} | All | 0 | | 9, 10, 11 | T _A = +25°C, -55°C & +125°C | ns |
| Address to Write Hold Time | t _{AH} | All | 0 | | 9, 10, 11 | T _A = +25°C, -55°C & +125°C | ns |
| Data Valid to Write Setup Time | t _{DS} | All | 70 | | 9, 10, 11 | T _A = +25°C, -55°C & +125°C | ns |
| Data Valid to Write Hold Time | t _{DH} | All | 10 | | 9, 10, 11 | T _A = +25°C, -55°C & +125°C | ns |
| Write Pulse Width | t _{WR} | All | 50 | | 9, 10, 11 | T _A = +25°C, -55°C & +125°C | ns |
| Minimum Load Resistance | R _{L(MIN)} | All | 2 | | 1, 2, 3 | Digital Inputs All Ones; T _A = +25°C, -55°C & +125°C | kΩ |
| V _{OUT} Slew Rate | SR | All | 2.5 | | 7 | T _A = +25°C | V/μs |

NOTES

¹V_{DD} = +15 V ± 10%, AGND = 0 V, DGND = 0 V, V_{SS} = 0 V unless otherwise specified.

²Includes full-scale error, relative accuracy, and zero code error.

³Digital inputs V_{IN} = V_{INL} or V_{INH}; V_{OUT} and V_{REFOUT} unloaded.

Table 2. Electrical Test Requirements for Class B Devices

| MIL-STD-883 Test Requirements | Subgroups (See Table 3) |
|---|-------------------------|
| Interim Electrical Parameters (Pre Burn-In) | 1 |
| Final Electrical Test Parameters | 1,* 2, 3 |
| Group A Test Requirements | 1, 2, 3, 7, 9, 10, 11 |

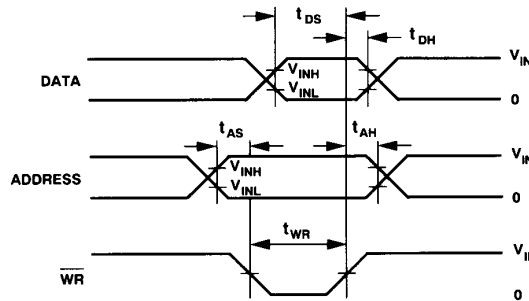
NOTE

*PDA applies to Subgroup 1 only. No other subgroups are included in PDA.

Table 3. Control Table

| Logic Control | | | DAC-8426 |
|----------------|----|----|-------------------------------------|
| WR | A1 | A0 | Operation |
| H | X | X | No Operation Device Not Selected |
| L | L | L | DAC A Transparent |
| \overline{L} | L | L | DAC A Latched |
| L | L | H | DAC B Transparent |
| \overline{L} | L | H | DAC B Latched |
| L | H | L | DAC C Transparent |
| \overline{L} | H | L | DAC C Latched |
| L | H | H | DAC D Transparent |
| \overline{L} | H | H | DAC D Latched |

L = Low State, H = High State, X = Don't Care.



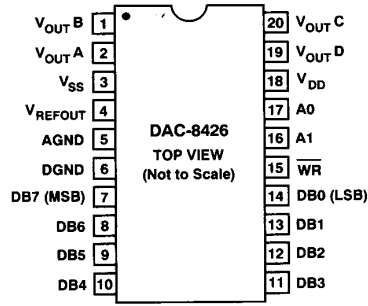
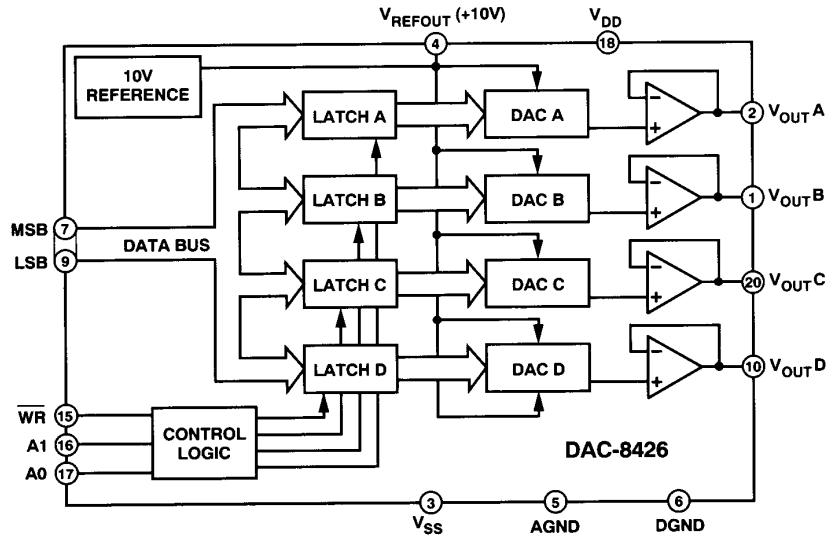
NOTES:

1. ALL INPUT SIGNAL RISE AND FALL TIMES ARE MEASURED FROM THE 10% TO 90% OF V_{DD} ($t_r = t_f = 20ns$ OVER THE V_{DD} RANGE)
2. TIMING REFERENCE LEVEL IS FROM $\frac{V_{INH} + V_{INL}}{2}$
3. $V_{IN} = 5V$

Write Timing Diagram

DAC-8426

3.2.1 Functional Block Diagram and Terminal Assignments.

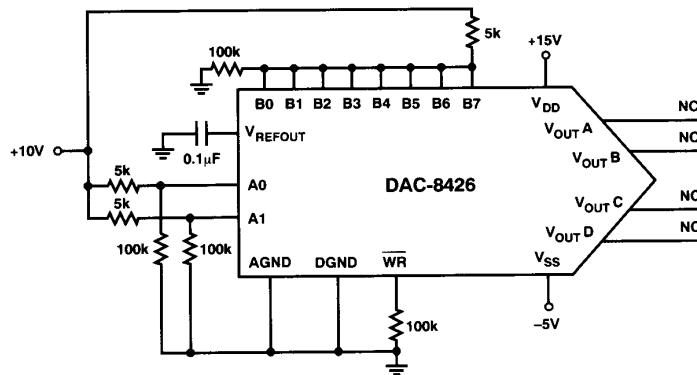


3.2.4 Microcircuit Technology Group.

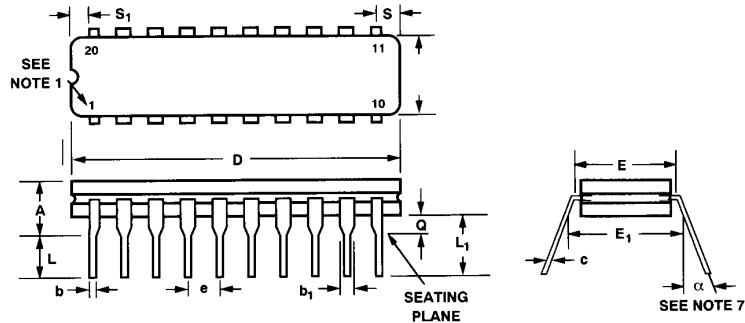
This microcircuit is covered by technology group 80.

4.2.1 Life Test/Burn-In Circuit.

Steady state life test is per MIL-STD-883 Method 1005. Burn-in is per MIL-STD-883 Method 1015 test condition (B).



20-Lead Ceramic DIP
(R Suffix)



20-Lead Ceramic DIP
(R Suffix)

| SYMBOL | INCHES | | MILLIMETERS | | NOTES |
|----------------|-----------|-------|-------------|-------|-------|
| | MIN | MAX | MIN | MAX | |
| A | | 0.200 | | 5.08 | |
| b | 0.014 | 0.023 | 0.36 | 0.58 | |
| b ₁ | 0.030 | 0.070 | 0.76 | 1.78 | 2 |
| c | 0.008 | 0.015 | 0.20 | 0.38 | |
| D | | 1.060 | | 26.92 | 4 |
| E | 0.220 | 0.310 | 5.59 | 7.87 | 4 |
| E ₁ | 0.290 | 0.320 | 7.37 | 8.13 | 7 |
| e | 0.100 BSC | | 2.54 BSC | | 5 |
| L | 0.125 | 0.200 | 3.18 | 5.08 | |
| L ₁ | 0.150 | | 3.81 | | |
| Q | 0.015 | 0.060 | 0.38 | 1.52 | 3 |
| S | | 0.080 | | 2.03 | 6 |
| S ₁ | 0.005 | | 0.13 | | 6 |
| α | 0° | 15° | 0° | 15° | |

NOTES

1. Index area; a notch or a lead one identification mark is located adjacent to lead one.
2. The minimum limit for dimension b₁ may be 0.023" (0.58 mm) for all four corner leads only.
3. Dimension Q shall be measured from the seating plane to the base plane.
4. This dimension allows for off-center lid, meniscus and glass overrun.
5. The basic lead spacing is 0.100" (2.54 mm) between centerlines.
6. Applies to all four corners.
7. Leads center when α is 0°. E₁ shall be measured at the centerline of the leads.

